

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 17.0001-01
CB Certificate No.: 50600165 ITL

Schedule Number: IECQ-L ULTW 17.0001-01-S Rev No.: 4 Revision Date: 2023/01/05 Page 1 of 2

Appendix-1 (50600165 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
I-V Probe station	WI-LM-0120
InGaAs microscope/Optical Beam Induced Resistance Change (OBIRCH)	WI-LM-0121
Scanning Acoustic Tomography (SAT)	WI-LM-0333
3D X-ray	WI-LM-0324
Secondary Electron Microscope (SEM)	WI-LM-0302
Electrostatic Discharge (ESD) / Latch-up (Heating by Thermo stream)	HBM: ANSI/ESDA/JEDEC JS-001/JESD22-A114 /
High Temperature Operating Life (HTOL)	JESD22-A108
Bias Life Test (BLT)	JESD22-A108
Early Failure Rate (EFR)	JESD22-A108
High Temperature Storage Life (HTSL)	JESD22-A103
Low Temperature Storage Life (LTSL)	JESD22-A108
Highly Accelerated Temperature And Humidity Stress Test (HAST)	JESD22-A110
Unbiased HAST	JESD22-A118
Pressure Cook Test (PCT)	JESD22-A102

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Temperature Cycling Test (TCT)	JESD22-A104
Thermal Shock Test (TST)	JESD22-A106
Precondition	IPC/JEDEC J-STD-020D Level 3, JESD22-A113

Technical Reviewer of DQS: Date: 01/05/2023

